

## 30V Dual N-Channel MOSFETs

### General Description

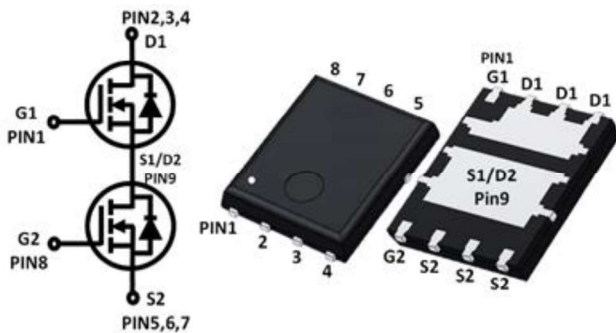
These Dual N-Channel enhancement mode power field effect transistors are using trench - technology. This advanced technology is designed to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche period. These devices are well suited for high efficiency fast switching applications.

	BV <sub>DSS</sub>	R <sub>DS(ON)</sub>	I <sub>D</sub>
Q1	30V	5.0mΩ	58A
Q2	30V	2.8mΩ	110A

### Features

- Improved dv/dt capability
- Fast switching
- 100% EAS Guaranteed
- Green Device Available

### PPAK5x6 Asymmetric Dual Pin Configuration



### Applications

- MB / VGA / Vcore
- POL Buck Applications
- SMPS 2<sup>nd</sup> SR

### Absolute Maximum Ratings (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Q1	Q2	Unit	
V <sub>DS</sub>	Drain-Source Voltage	30	30	V	
V <sub>GS</sub>	Gate-Source Voltage	±20	+20/-16		
I <sub>D</sub>	Drain Current-Continuous <sup>A</sup>	T <sub>A</sub> = 25°C	18	27	A
		T <sub>A</sub> = 70°C	14	20	
		T <sub>C</sub> = 25°C	58	110	
		T <sub>C</sub> = 100°C	34	65	
I <sub>DM</sub>	Drain Current-Pulsed <sup>A, B</sup>	T <sub>A</sub> = 25°C		125	240
I <sub>AS</sub>	Non-repetitive Avalanche Current <sup>E</sup>	25	36		
E <sub>AS</sub>	Single Pulse Drain-to-Source Avalanche Energy <sup>E</sup>	31.2	64.8	mJ	
P <sub>tot</sub>	Maximum Power Dissipation	T <sub>A</sub> = 25°C	3.1	3.6	W
		T <sub>C</sub> = 25°C	31.3	54.3	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +150		°C	

### Thermal Characteristics

Symbol	Parameter	Conditions	Q1	Q2	Unit
R <sub>θJA</sub>	Junction-to-Ambient <sup>C</sup>	Steady State	40	35	°C/W
R <sub>θJC</sub>	Junction-to-Case	Steady State	4	2.2	°C/W

## Q1\_Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

### Static State Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	30	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 27V, V <sub>GS</sub> = 0V	-	-	1	μA
		V <sub>DS</sub> = 24V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125°C	-	-	10	μA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±20	μA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.2	1.7	2.5	V
R <sub>DS(on)</sub>	Drain-Source On-State Resistance	V <sub>GS</sub> = 10V, I <sub>DS</sub> = 20A	-	4.2	5	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>DS</sub> = 15A	-	6.4	8.3	mΩ
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> = 5V, I <sub>D</sub> = 30A	-	18	-	S

### Dynamic Characteristics Note D

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1MHz	-	840	-	pF
C <sub>oss</sub>	Output Capacitance		-	580	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	35	-	pF
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> = 0V, f = 1MHz	-	1.3	-	Ω
Q <sub>g</sub>	Total Gate charge	V <sub>GS</sub> = 10V	-	15	-	nC
		V <sub>GS</sub> = 4.5V	-	7.2	-	nC
Q <sub>gs</sub>	Gate to Source Charge	V <sub>DD</sub> = 15V, I <sub>DS</sub> = 30A	-	3.4	-	nC
Q <sub>gd</sub>	Gate to Drain Charge		-	2.8	-	nC
T <sub>d(on)</sub>	Turn-On Delay Time		-	6	-	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15V, V <sub>GS</sub> = 10V,	-	78	-	ns
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>DS</sub> = 30A, R <sub>G,ext</sub> = 3Ω	-	13	-	ns
t <sub>f</sub>	Fall Time		-	81	-	ns

### Drain-Source Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I <sub>S</sub>	Diode continuous forward current		-	-	58	A
I <sub>SM</sub>	Diode pulse current <sup>B</sup>		-	-	125	A
V <sub>SD</sub>	Diode Forward Voltage <sup>B</sup>	V <sub>GS</sub> = 0V, I <sub>S</sub> = 1A	-	-	1	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>S</sub> = 30A, di/dt = 100A/μs	-	22	-	ns
Q <sub>rr</sub>	Diode Reverse Recovery Charge		-	11	-	nC